

## Electronic Design Automation (EDA) Tools and Considerations for Electro-Thermo-Mechanical Co-Design of High Voltage Power Modules

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**College of Engineering** *Mixed-Signal Computer Aided Design Research Lab* 

# Outline

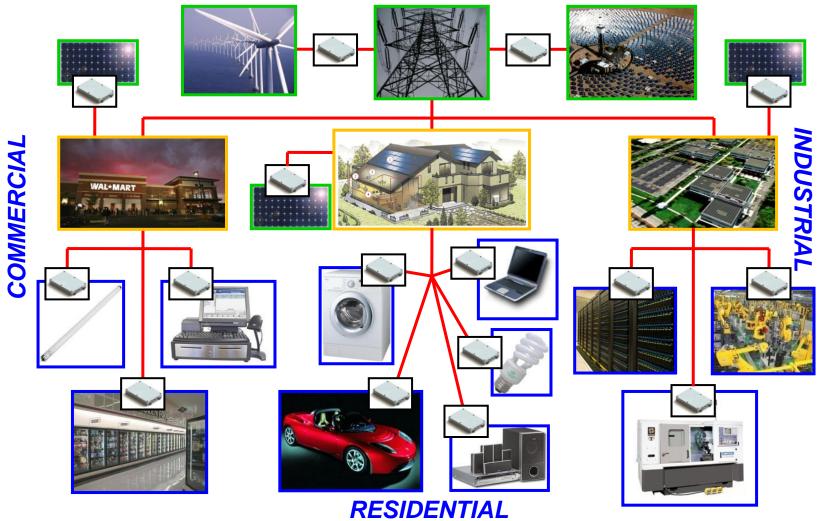


- Motivation
- PowerSynth Introduction
  - Overview
  - Models
  - High voltage reliability constraints
- ParaPower Introduction
- EDA tool integration
- Co-design example
- Summary

## Power Electronics is Everywhere



#### **ELECTRIC GENERATION**



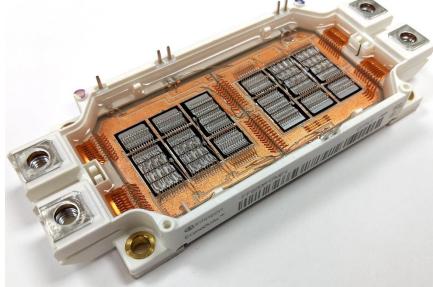
## MCPM Co-Design Challenges



# Physical design of multi-chip power modules (MCPM) is time consuming and poses several challenges:

 Multi-domain nature of power electronic packaging necessitates consideration of materials and designs towards reduced:

- Electrical parasitics for high performance devices
- Temperature and mechanical stress for higher reliability
- Traditional design flows are iterative and require extensive use of computationally expensive finite element analysis (FEA)



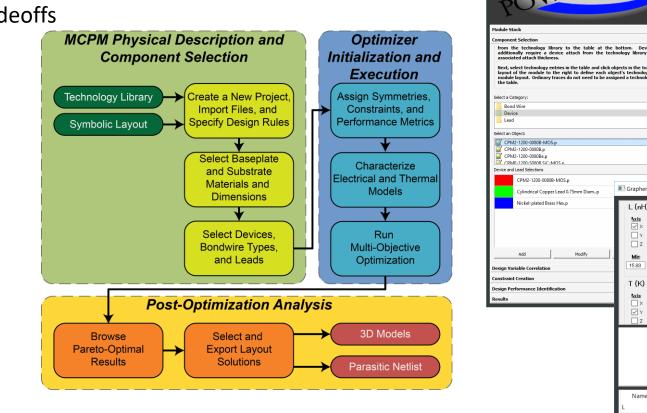
## PowerSynth Overview

E PowerSynth

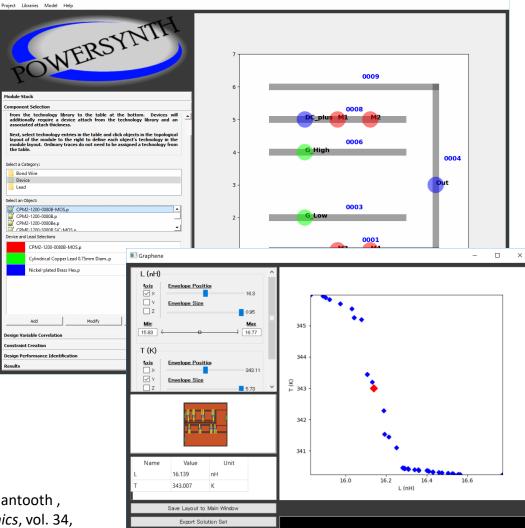


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- EDA tool for multi-chip power modules (MCPM)
- Multi-objective layout optimization
- Reduced order models
- Pareto-front of tradeoffs
- Design export



Tristan M. Evans, Quang Le, Shilpi Mukherjee, Imam Al Razi, Tom Vrotsos, Yarui Peng, H. Alan Mantooth, "PowerSynth: A Power Module Layout Generation Tool," in *IEEE Transactions on Power Electronics*, vol. 34, no. 6, pp. 5063-5078, June 2019. doi: 10.1109/TPEL.2018.2870346 Highlighted Paper



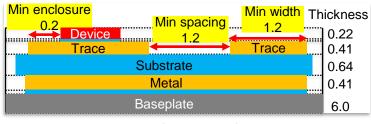
# PowerSynth Manufacturer Design Kit (MDK) and Technology Library

## Layer Stack

- Input file describing layers and technologies
- Holds information pertaining to
  - Layer width, length, and thickness
  - Layer material properties

# MDK and Design Rules and Checker (DRC)

- Input file containing technologydependent design and processing rules
- Ensures feature sizing and component placement are within processing tolerance



MCPM layer stack

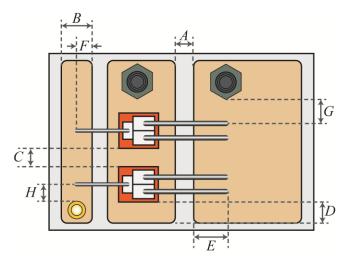
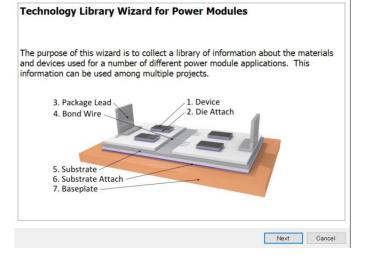


Illustration of design rules pertaining to feature placement and minimum spacing



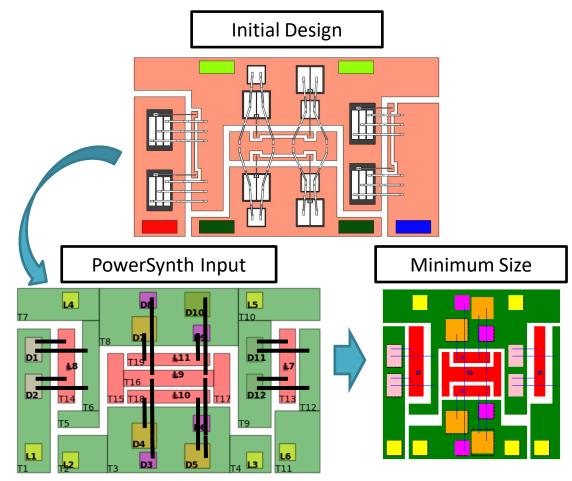


#### PowerSynth technology library wizard

## PowerSynth Layout Engine



- Constraint aware, hierarchical layout engine
- Minimum trace gaps set by trace-to-trace potential difference
- Heterogeneous component support
- Fixed or minimum layout size capabilities



I. Al Razi, Q. Le, H. A. Mantooth, and Y. Peng, "Constraint-Aware Algorithms for Heterogeneous Power Module Layout Synthesis and Reliability Optimization." in 2018 IEEE 6<sup>th</sup> Workshop on Wide Bandgap Power Devices and Applications (WiPDA), 2018, pp. 323-330.

## PowerSynth Thermal Model



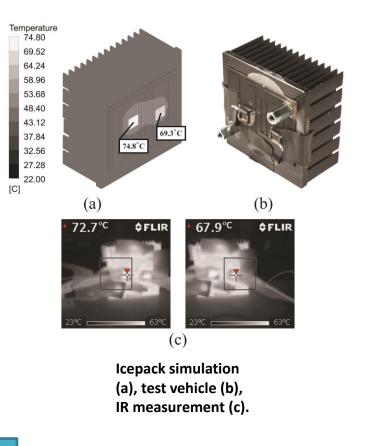
#### **Fast Thermal Model**

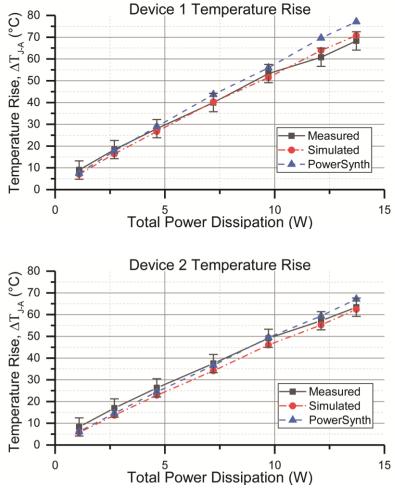
- Lumped element heat transfer system composed of thermal resistances
- Single FEA sim for characterization
- Includes mutual heating and proximity effects

#### **Device temperature rise results**

- PowerSynth thermal model, Icepak, and thermal camera measurement comparison
- Average error of 4% when compared to simulation or measurement

PowerSynth accuracy within 10% but 8000x faster than FEA





Thermal model validation results for device 1 (above) and device 2 (below) of the test vehicle over a range of power dissipation levels

## **PowerSynth Electrical Model**





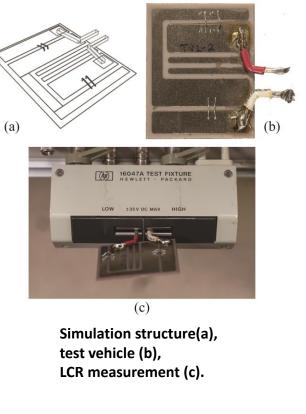
#### **Response surface model (RSM) for parasitics**

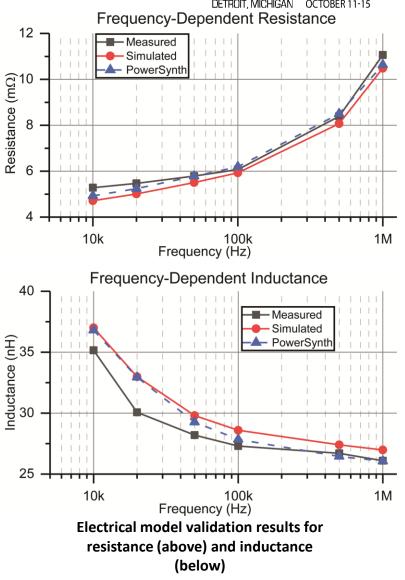
- Based on partial element equivalent circuit method (PEEC)
- Uses FastHenry to run parametric simulations for a given substrate technology
- Maps trace dimensions and vertical separation to resistance and inductance values

#### **Resistance and inductance results**

- Test vehicle layout parasitics compared among PowerSynth, FastHenry, and LCR meter measurement
- PowerSynth model error <10% with both simulation and measurement

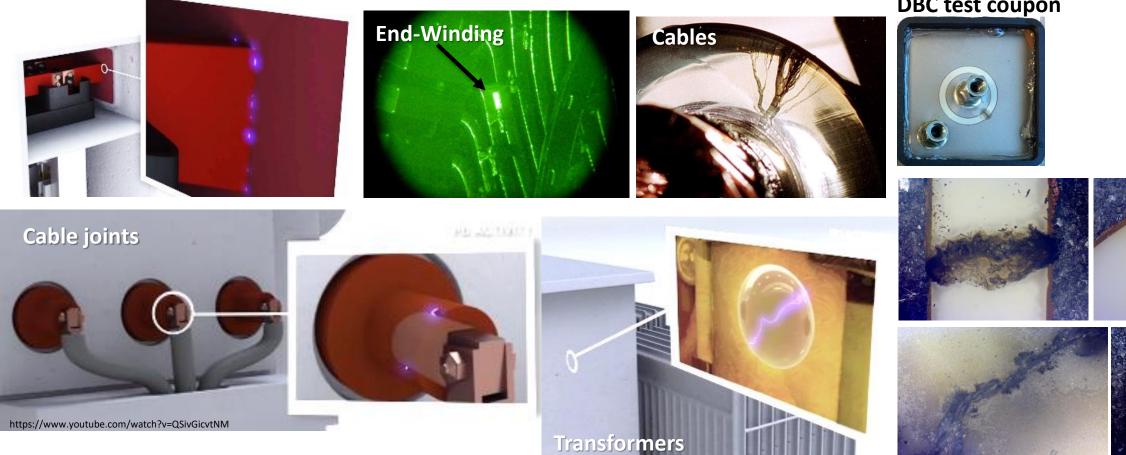
RSM parasitics calculation is accurate and up to 6000 times faster than simulation





## Partial Discharge (PD) and High Voltage Reliability



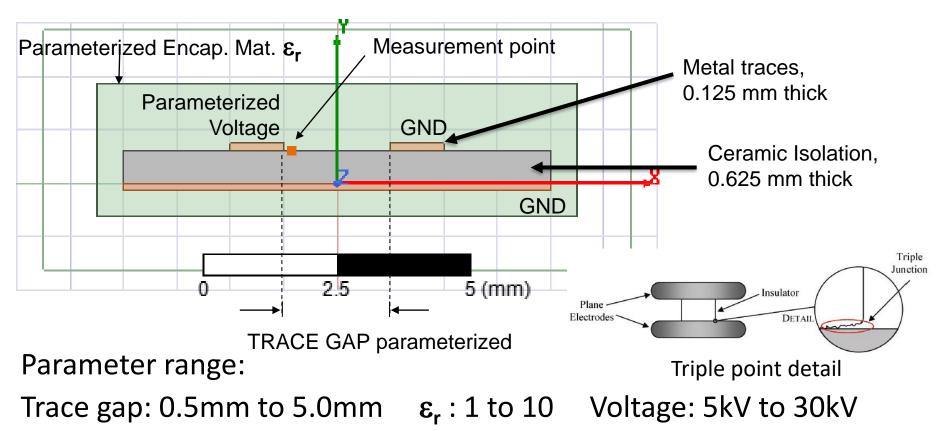


**DBC test coupon** 



# 2D Electric Field Simulation Setup

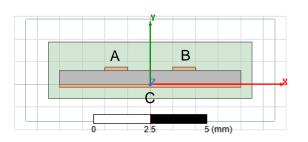
### Model geometry



## **2D Electric Field Simulations**

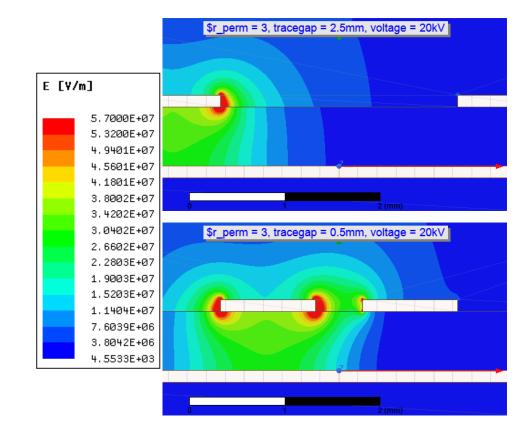


## Model geometry



Parameter range:

Trace gap: 0.5mm to 5.0mm step size: 0.5mm  $\epsilon_r$ : 1 to 10 step size: 1 Voltage: 5kV to 30kV step size: 5kV



# 2D Electric Field Simulation Results



## General form of equation

### Power curves

$$E = f(v, \varepsilon_r) x^{-g(v, \varepsilon_r)}$$

Where

E is the electric field in kV/mm,

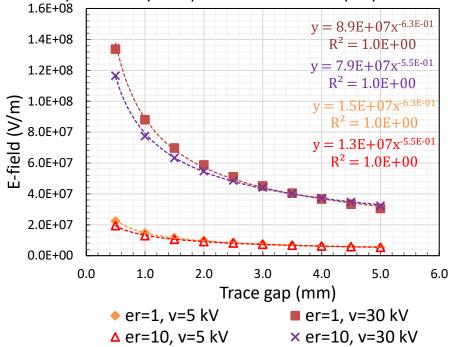
v is the voltage in kV,

x is the gap between traces A and B in mm,

 $\varepsilon_r$  is the relative permittivity of the encapsulating material

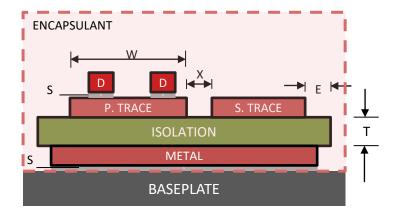
f and g are functions of v and  $\varepsilon_r$ .

E-field vs. trace gap for corner cases of the parametric sweep of voltage and relative permittivity at a point close to the triple point



## Implementation in PowerSynth





W: lateral width of trace

- X: lateral trace gap
- E: minimum enclosure

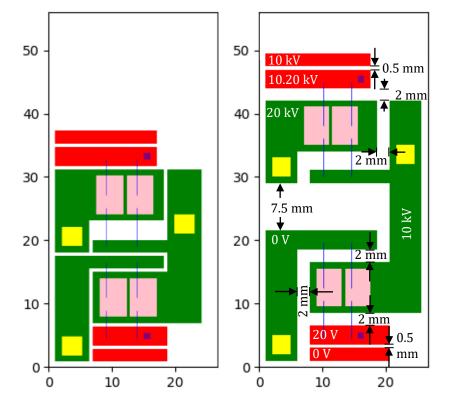
T: vertical thickness of a layer

D: device

P. trace: power trace; S. trace: signal trace

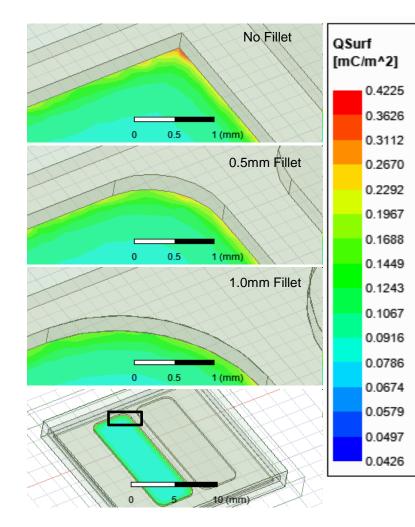
S: substrate attach or die attach

## Default layout vs. Layout with design rules applied

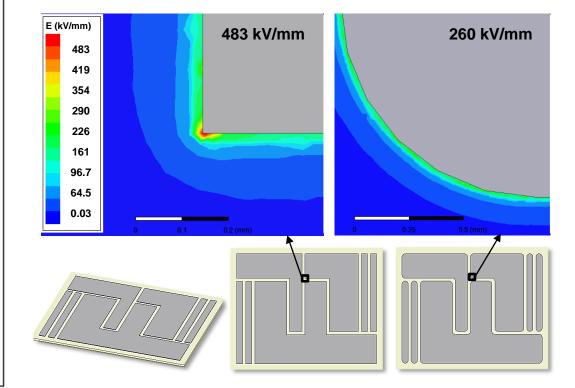


## Effect of Filleting Sharp Corners





E-field and Q<sub>s</sub> are almost halved



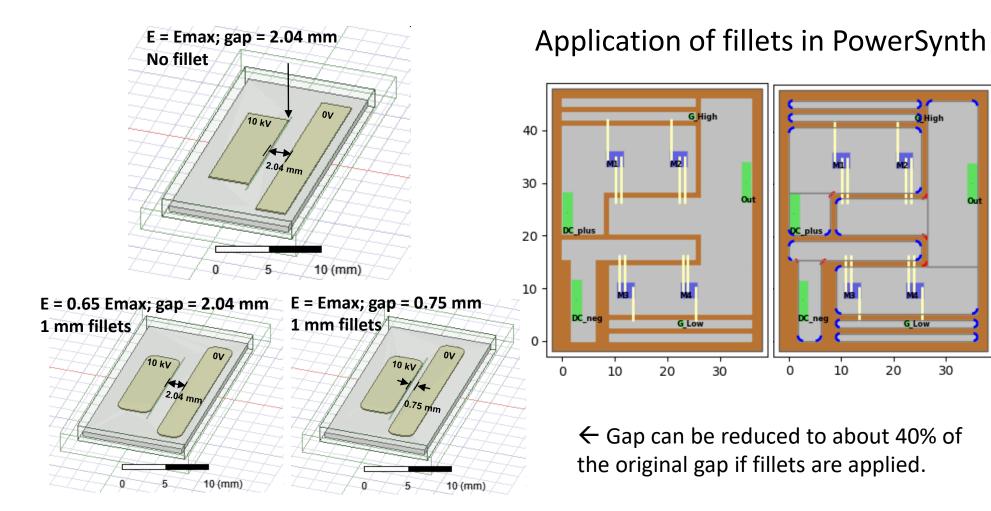
# IEEE ENERGY CONVERSION CONGRESS & EXPO

#### **Bottom view** Top view D: Static Structural Equivalent Stress 2 Max stress = 301 MPa Type: Equivalent (von-Mises) Stress Unit: Pa Time: 1 7/15/2020 1:12 PM 3.0092e8 Max 2.7491e8 Max Sharp 2.4889e8 2.2288e8 1.9686e8 1.7085e8 1.4483e8 1.1882e8 0.02 (m) 9.2805e7 0.01 0.02 (m) 0.005 0.015 6.6791e7 Min 0.005 0.015 F: Static Structural\_fillet Equivalent Stress 2 Max stress = 247 MPa; 18% reduction. Type: Equivalent (von-Mises) Stress Unit: Pa Time: 1 Fillet 7/15/2020 1:09 PM 2.4744e8 Max 2.287e8 2.0997e8 1.9123e8 1.7249e8 1.5375e8 1.3501e8 1.1627e8 0.005 0.015 0.02 (m) 9.7536e7 7.8798e7 Min 0.005 0.015

**Filleting Reduces Mechanical Stress** 

# Effect of Filleting Sharp Corners with PowerSynth





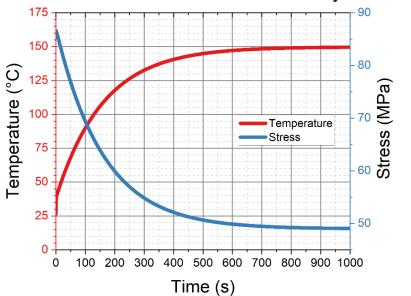
## ParaPower Overview



- Open source co-design tool by US Army Research Lab
- Fast, thermomechanical analysis of power electronics modules
- Parametric analysis tools
- Support for phase change materials

ARL ParaPower Environmental Parameters									Initial Temperature (C): 20							
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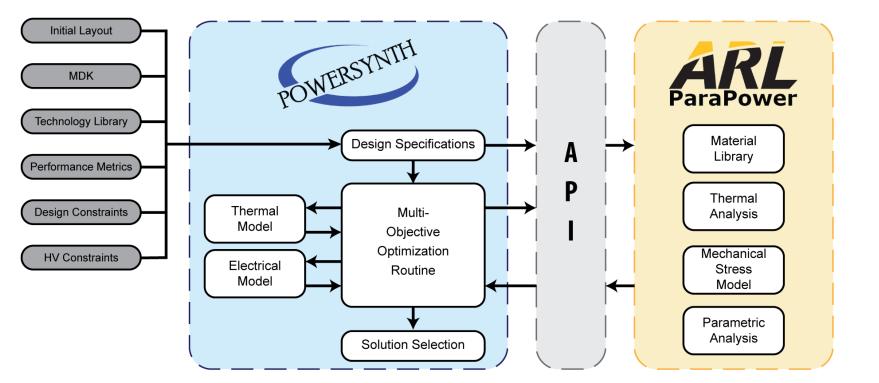
#### Transient Thermo-Mechanical Analysis





## 





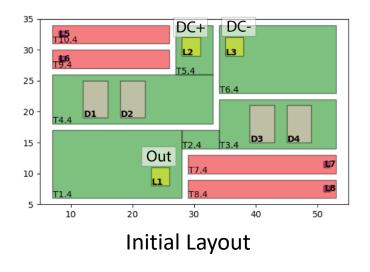
## **API to leverage:**

- PowerSynth layout generation and electrical parasitics extraction
- ParaPower 3D thermo-mechanical analysis

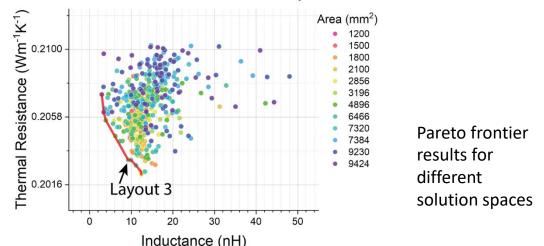
# Co-Design Example (1/2)

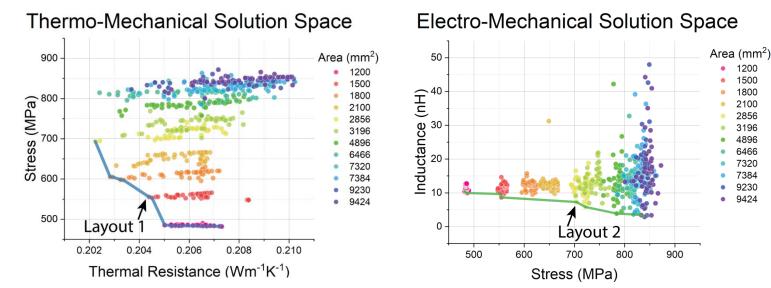


- Half bridge layout
- Loop inductance from DC+ to DC-
- 10 W power dissipation/die, 25°C backside temperature
- 230°C process temperature, -40°C minimum ambient temperature



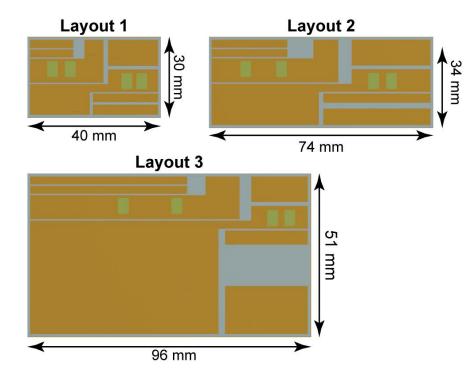
**Electro-Thermal Solution Space** 





## Co-Design Example (2/2)





### Layouts performance metrics

	Dimensions (mm)	Inductance (nH)	R <sub>TH</sub> (Wm <sup>-1</sup> K <sup>-1</sup> )	Stress (MPa)
Layout 1	40x30	9.93	0.204	556
Layout 2	74x34	7.23	0.206	704
Layout 3	96x51	9.26	0.203	816

Layouts selected from solution space

# Summary and Future Work



- EDA tools for power electronics gaining momentum
- Integration of PowerSynth and ParaPower enhances capabilities of both
- Layout engine updated with high voltage reliability constraints
- Co-design methods being used to rapidly explore design space tradeoffs
- Continued development:
  - Enhance models
  - Toward 3D and heterogeneous layout
  - Reliability assessment

## Acknowledgements







Power Optimization of Electro Thermal Systems (POETS) An NSF ERC US Army Research Laboratory



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